

<b>Notice of References Cited</b>	Application/Control No. 09/327,282	Applicant(s)/Patent Under Reexamination JEONG ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,922,240	05-1990	Duwaer, Arne L.	345/100
	B	US-6,175,351	01-2001	Matsuura et al.	345/98
	C	US-5,568,163	10-1996	Okumura, Fujio	345/100
	D	US-6,064,459	05-2000	Lee, Dae-won	349/139
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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